

**Notice of References Cited**

Application/Control No.

09/937,149

Applicant(s)/Patent Under  
Reexamination  
KOHIKI ET AL.

Examiner

Kallambella Vijayakumar

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kohiki et al, "Enhanced Conductivity of Zinc Oxide thin films by ion implantation of hydrogen atoms", Appl. Phys. Lett. 1994, Vol. 64, Pp 2876-2878.
	V	Walle, "Hydrogen as a cause of Doping in Zinc Oxide", Physical Review Letters, 2000, Vol. 85(5), pp 1012-1015
	W	Ryuta et al, "Preparation and characterization of In <sub>2</sub> O <sub>3</sub> :Li(x=0-1.0)", Nippon Kagaku Kaishi 1999, Volume-5, pp 323-327.
	X	Sasaki et al, "Preparation and characterization of Lithium doped Indium Sesqui Oxide", J. Alloys and Compounds, 2001, 322, p 220-225.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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